



ISO/TC 130 N 1354
TC130/JWG8 N 077
TC130/WG3 N 747

[ISO/TC 130](#)

Graphic technology

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Secretariat: DIN

minutesJWG8 Amsterdam 2008-09-22

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Minutes of the 5th meeting of ISO TC 130/JWG 8 Revision of ISO 13655, Amsterdam, 2008-09-22 [afternoon]

1 Opening of the meeting

Andreas Kraushaar opened the meeting and welcomed the participants. He warmly thanked the Wilko de Groot (IGT) for hosting the meeting and Karin Winkelmann for writing the minutes.

2 Roll call of experts and observers

A roll call of experts was held. The scanned attendance list is given in Annex 1 to these minutes.

Karin Winkelmann has expressed that only a few national member bodies has entries about their experts in the ISO Global Directory (ISO GD). Based on information from ISO/CS and DIN - starting from 2009 - only experts registered in the ISO GD can be accepted officialy as representatives from their country and will get access to the documents via Livelink. The experts were requested to check the current entries in the ISO-GD and to undertake appropriate steps, see Annex 2.

3 Approval of draft agenda

The draft agenda was slightly modified and than reviewed (See ISO/TC130/JWG 8 N 68). It was amended to incorporate additional presentations and results from the email review. The agenda was then approved.

4 Review and approval of notes from the prior Paris meeting

The reports of the previous Paris meeting were accepted (ISO/TC130/JWG 8 N 57).

5 Review and discussion of remaining action items

The table of action items given in document ISO/TC 130/JWG 8 N 57 was reviewed by the working group. In the light of the discussion followed the Paris meeting Mr. Kraushaar proposed to close the action items 08-01 until 08-04. This is due to the fact that they became obsolete.

	<i>Who</i>	<i>What?</i>	<i>Status (open, close)</i>
08-01	Kraushaar	Distribute resolved comments 1 through 128 for 30 day review	Close
08-02	Kraushaar	Provide proposed resolution of comments for items 129 – 195 and distribute for 30 day review.	Close
08-03	Kraushaar	Prepare proposed publication draft and distribute for 60 day review.	Close
08-04	Kraushaar	Consolidate comments on proposed publication draft and distribute prior to Amsterdam meeting	Close

6 Identification of new documents

New documents since Paris meeting are: N 57 to N73

7 Discussion of status quo – How to move forward?

Mr. Kraushaar gave a presentation (N 74) summarizing the status quo of the document. Contrary to the way forward as planed at the Paris meeting a second DIS might be necessary. This was caused by discussions around ISO 5-3, requesting an additional measurement condition called "M0". This is to allow the practical data exchange of historical spectral data and to calculate density from spectral data. "M0" provides for a measurement condition that accommodates this need for

densitometry, and if colorimetry data is calculated from the same data a way to unambiguously identify this. After a presentation by Mr. Lanat (N 76), that nicely showed the colorimetric readings and differences between different instruments such as Elrepho and the XRite EyeOne on different paper types, the group discussed the incorporation of such an additional condition "M0". Mr. Kraushaar raised concerns of possible irritations in the later usage of that standard since both measurement conditions "M0" and "M1" aiming for the same use case, which was called "colour management by default". Workflow applications such as the definition of aim data, characterization data, measurements and validations for proof or press quality control have been mentioned as possible examples.

After some discussions about the pros and cons of such incorporation the group decided in favour of an additional condition "M0" while tightening the requirements for the measurement condition "M1" at the same time (see action items 08-05 and 08-06). Dr. Green, Mr. McDowell and Mr. Lanat particularly emphasized the importance of a rigorous definition of the UV portion of the light source used. The evaluation method (virtual metamers in the uv-region) defined in ISO 3664 (referring to CIE 51 and CIE S12 now also available as ISO 23603) should be used for assessment (see action item 08-07).

A second aspect raised by the presentation from Ito san (N 75) is the conformance definition for the measurement condition "M2" (UV-Cut measurements). He reported on recent findings concerning how practical graphic art instruments do conform to both the definition stipulated in the CD-document and the updated procedure defined in annex H. He concluded that using the new method the majority of the instruments tested fulfill the requirements. Anyhow he proposed to change the Wratten filter by a manufacturer independent spectral definition, see action item 08-08.

8 Discuss the Paris comments and the following email review

Discuss path forward (second DIS?)

After the incorporation of "M0" and the "M2"-conformance level have been addressed final comments from the US delegation concerning the draft document of the email review were resolved. Both this document ("ISO_DIS13655_Draft_30dayreview_after_Paris") and the proposed resolution of comments will be distributed via livelink. The latter one will be supplemented by the CIE comments, to be submitted before the Paris meeting as sticky notes, converted to "ISO style" by Dr. Green (see action item 08-09).

Based on that Mr. Kraushaar will provide a revised document including the resolved comments by the end of October. This document will be circulated within JWG8 via email review. It is subject for the final comments to be provided by Cheydeur (see action item 08-05). After this input has been made a final document should be provided by the editor for a second DIS ballot. In order to facilitate enough time for the ISO editor and the 3-month DIS ballot this should be done not later than the mid of January 2009.

In order to avoid the cancellation of the project (in case the DIS ballot will be delayed) Karin Winkelmann proposed to change the timeframe for ISO 13655 from 36 to 48 month.

9 Liaison matters

9.1 ISO/TC42/JWG 21 (ISO 5 series)

It was reported that all parts of ISO 5 were available as DIS draft documents. The comments on these documents will be reviewed in the planned meeting of JWG21 on Friday September 26th.

9.2 ISO/TC42/JWG 24 (ISO 3664)

Mr. McDowell reported on the upcoming JWG24 meeting to be held in cologne.

10 Summary of Amsterdam action items

No.	Who	What?	Status (open, close)
08-05	Cheydleur, McDowell, Lanat	To Incorporate the principles proposed by Ray into specific edit changes for ISO/DIS 13655 (including the conformance requirement)	Open
08-06	McDowell,	Change illuminant conformance to shall and change text accordingly	Open
08-07	Lanat, Kraushaar, McDowell	To provide additional information (correlation) concerning the ISO 3664 Ml _{uv} evaluation. The latest should be mentioned in a note (UV calibration by illuminant C)	Open
08-08	Cheydleur, Ito	To substitute the Wratten filter in Annex H by a spectral definition independent of any filter manufacturer (recommend commercial filters such as from Fuji or Kodak)	Open
08-09	Green, Lanat	To “convert” the CIE comments to ISO style	Open
08-10	Kraushaar, Rich, McDowell, Green	To resolve US comment 18 on the email review (5 and 1nm usage)	Open
08-11	Lanat, Hossli	To perform a evaluation of which instruments fulfill the M2 conformance level	Open
08-12	Lanat	to create a liaison report concerning TC6 work on optical properties in general	Open

11 Requirements concerning the future meeting




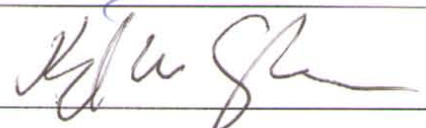

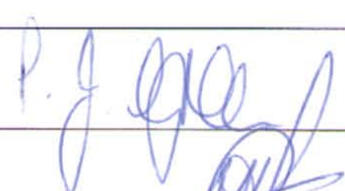


Mr. Kraushaar will ask for 1/2 day time slot in the Dallas meeting to review comments on the consolidated draft of the second DIS ballot to be than send to ISOCS for final publication.

12 Any other business

Mr Kraushaar thanked the participants for their contributions and closed the meeting.

Attendance List

5th Meeting of ISO/TC 130/JWG 8 on 22 September 2008, Amsterdam

Name	Country	Signature
Kraushaar, Andreas	DE	
Winkelmann, Karin Dipl.-Ing.	DE	
Abbott, Mary	US	
Belz, Harry DIECKHOFF, FRANK	DE	
Cheydleur, Raymond	US	
Chop, Kevin	US	
Egawa, Yuji	JP	
Ehbets, Peter Dr.	CH	
Gaykema, Frans	NL	
Green, Phil	GB	
de Groot, Wilco	NL	
Heid, Wilhelm	DE	
Holm, Jack	US	
Ito, Akihiro	JP	
Khoury, Elie	FR	



ISO/TC 130/JWG 8 Joint TC 130-TC 42 WG: Revision of ISO 13655

Attendance List

5th Meeting of ISO/TC 130/JWG 8 on 22 September 2008, Amsterdam

Name	Country	Signature
McCarthy, Ann L	US	
McDowell, David Q.	US	
Meinecke, Karl M.	DE	
Orf, Debbie	US	
Peyton, James A.	US	
Presley, Richard	US	
Rangel, Rose	BR	
Rich, Danny Dr.	US	
Rodriguez, Michael Dr.	US	
Rupyshev, Viktor	RU	
Ruttanasirimaneevate, Prajak	TH	
Seymour, John	US	
Smiley, Steve	US	
Soares Stucchi, Aparecida	BR	
Sunderland, Bryan	GB	



ISO/TC 130/JWG 8 Joint TC 130-TC 42 WG: Revision of ISO 13655

Attendance List

5th Meeting of ISO/TC 130/JWG 8 on 22 September 2008, Amsterdam

Name	Country	Signature
Tangvichachan, Theera Prof.	TH	
Thongpetch, Supree	TH	
Urabe, Sunao <i>Hitoshi</i>	JP	<i>Hitoshi Urabe</i>
Vandenbroucke, Dirk Dr. Sci.	BE	
Warner, Lawrence C.	US	
Widmer, Erwin	CH	<i>E. Widmer</i>
Wychorski, Philip	US	
Zhiyong, Ma	CN	
<i>Luetkens, Heide</i>	US	
Beckmann, Beatrix	DE FRA Liaison	
<i>FONS PUT, VIGC</i>	B	
<i>Kees van Middelkoop, IGT</i>	NL	<i>Kees van Middelkoop</i>
<i>Andri J. Verhoeven SGI</i>	NL	

in de Attendance list staat ook Hitoshi

MASAAKI MATSUO

JP

Matsuo



ISO/TC 130/JWG 8 Joint TC 130-TC 42 WG: Revision of ISO 13655

Attendance List

5th Meeting of ISO/TC 130/JWG 8 on 22 September 2008, Amsterdam

Name	Country	Signature
Barros, Gil Dr.	SE	
Berthold, Uwe Dr.	DE	
Bestmann, Günter Dr.	DE	
Carnelli, Carlo "G"	IT	
Garcia-Maroto Rosas, Julio Sousa, Elcio	BR	
Hannemann, Peter	DE	
Hansuebsai, Aran	TH	
Hossli, Gallus	DE	
Kaizaki, Hajime	JP	
Lanat, Luc	FR	
Matsuki, Makoto	JP	
Pate, Laurie	GB	
Urabe, Hitoshi	JP	

Tim C. Cleypote uk.

Entries in ISO Global Directory

<p>Committee: ISO/TC 130/WG 2</p>	<p>Members Roles</p>
<p>Parent: ISO/TC 130</p>	<p>Working Group</p>
<p>Committee member: Soares Stucchi Aparecida Ms @ ABNT/ONS-27 Rangel Rose Mrs. @ ABNT Mortara Bruno Arruda Mr @ ABNT/ONS-27 McDowell David Q. Mr. @ NPES Holm Jack Mr. @ HP Palo Alto Abbott Mary @ ANSI Donahue Timothy Mr. @ Eastman Kodak Iobst John Dr. @ Newspaper Association of America Isaacs Dov Dr. @ Adobe San Jose Kelly Dwight Mr. @ Apago, Inc. Reese Janice Ms. @ Network PDF Rosenthol Leonard Mr. @ Adobe Systems Schowalter Chris Mr. @ GMG Americas Smiley Steve Mr. @ Vertis Tastl Ingeborg Dr. @ HP Palo Alto Warter Lawrence Mr. @ Enovation Graphic Systems, Inc. Prouty Dave Mr. @ Hewlett Packard Boise Rodriguez Michael Dr. @ RR Donnelley Premedia Technologies Ackner Reuven Mr. @ EFI Chevdleur Raymond W. @ X-Rite, Inc. Kita Danny @ Optio Software Den Tandt Andy @ ANSI Experts Sekine Hitoshi Mr. @ Ricoh Americas Corporation Aronshtam Boris @ ANSI Experts Orf Debbie @ ANSI Experts Cecchi Ann @ Xerox Corporation - XIPO Williams David A. @ Ricoh Americas Corporation Benson Craig @ Adobe Systems, Inc. Kahana Gal @ XMPie Wahrmann Luci @ ANSI Experts Bailey Martin Mr. @ ECMA - Cylinder Revie Craig @ BSI Experts Sunderland Bryan @ BSI Experts Clarke Peter Dr @ Tintometer Kraushaar Andreas Mr @ DIN Experts Wischhöfer Cord Mr @ DIN Beckmann Beatrix Mrs @ DIN Experts Brües Stefan Prof. Dr. @ DIN Experts Drümmer Olaf Mr @ DIN Experts Meinecke Karl M. Mr @ DIN Experts Schaul Ronald Mr @ DIN Süßli Florian Mr @ DIN Experts Battrick George Mr @ ERA Prosi Rainer Dr. @ DIN Experts Winkelmann Karin Dipl.-Ing. @ DIN Heid Wilhelm Mr @ DIN Experts Rupyshev Viktor Mr. @ GOST R Experts Urabe Hitoshi @ JISC 042 Matsuki Makoto @ JISC 130 Yuasa Tomonori @ JISC 130 Myoki Yutaka @ JISC 130 Osada Koichi @ JISC 130 de Groot Wilco Mr. @ IGT Zhiyong Ma @ SAC Barros Gustavo Gil Mr @ SIS Experts Jaeggi Stephan Mr. @ SNV Widmer Erwin Mr. @ SNV Ruttanasirmaneevate Prajak @ TISI Hansuebsai Aran @ Chulalongkorn University Koopipat Chawan @ Chulalongkorn University Thongpetch Supree @ Colour Doctor Co., Ltd. Songsermsawas Santi @ Aksornsobhon Co.,Ltd.</p>	<p>Members Roles</p> <p>Actions</p> <p>Read</p> <p>Balloting Roles</p> <p>Liaisons</p> <p>Projects</p>
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Widmer Erwin Mr. @ SNV	
Pungrasamee Pontawee @ Chulalongkorn University	
Pachonklaew Pakamas @ Sukhothai Thammathirat Open University	Projects
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[Hansuebsai Aran @ Chulalongkorn University](#)
[Koopipat Chawan @ Chulalongkorn University](#)
[Katemake Pichayada @ Chulalongkorn University](#)

Centralized Committee member:

Serial Number: 52222

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[Rich Danny Dr. @ Sun Chemical Corporation](#)
[Presley Richard Mr. @ Eastman Kodak](#)
[Chop Kevin Mr. @ Diageo](#)
[Orf Debbie @ ANSI Experts](#)
[Abbott Mary @ ANSI](#)
[Cheydleur Raymond W. @ X-Rite, Inc.](#)
[Seymour John Mr. @ QuadTech](#)
[Warter Lawrence Mr. @ Enovation Graphic Systems, Inc.](#)
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[Heid Wilhelm Mr @ DIN Experts](#)

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